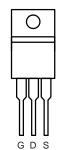


PHP36N03LT-VB Datasheet N-Channel 30-V (D-S) MOSFET

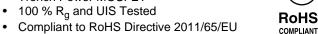
PRODUCT SUMMARY					
V _{DS} (V)	30				
$R_{DS(on)}$ (Ω) at V_{GS} = 10 V	0. 006				
$R_{DS(on)}$ (Ω) at V_{GS} = 4.5 V	0. 009				
I _D (A)	80				
Configuration	Single				
Package	TO-220AB				

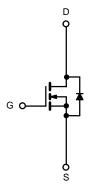
TO-220AB



FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested





N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S (T _A = 25 °C, unle	ss otherwise n	oted)		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	- V	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		80		
	T _C = 70 °C		65		
	T _A = 25 °C	I _D	25.8 ^{b, c}		
	T _A = 70 °C		20 ^{b, c}		
Pulsed Drain Current		I _{DM}	200		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39		
Single Pulse Avalanche Energy	L = 0.1 IIIH	E _{AS}	94.8	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	50 ^{a, e}	A	
	T _A = 25 °C	'S	3.13 ^{b, c}	A	
Maximum Power Dissipation	T _C = 25 °C		120 ^a		
	T _C = 70 °C	P _D	85	w	
	T _A = 25 °C	- O	3.75 ^{b, c}	vv	
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Ra	ange	T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6		

Notes: a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board. c. t = 10 sec. d. Maximum under steady state conditions is 90 °C/W. e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

HP36N03LT-VB				(AB,	VBse	
					www.VI	Bsemi.	
SPECIFICATIONS (T _J = 25 °C,	unless othe	rwise noted)					
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η – 200 μΑ		- 7.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Oala Malla na Daria Oana at		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$					
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			Α	
		V _{GS} = 10 V, I _D = 28.8 A		0.006			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 30 A		0.009		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 28.8 A		160		S	
Dynamic ^b						1	
Input Capacitance	C _{iss}			1600		pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		525			
Reverse Transfer Capacitance	C _{rss}			370			
		$V_{DS} = 15 V_{.} V_{CS} = 10 V_{.} I_{D} = 28.8 A$		35	45	+	
Total Gate Charge	Qg			25	35	nC	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 28.8 A		15			
Gate-Drain Charge	Q _{gd}			20		-	
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{1} = 0.625 \Omega$		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 24 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_g = 1 \Omega$		70	105		
Fall Time	t _f	-		10	15		
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V_{DD} = 15 V, R _L = 0.67 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		55	83		
Fall Time	t _f	`		12	18	1	
Drain-Source Body Diode Characteristic				1		I	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			120		
Pulse Diode Forward Current ^a	I _{SM}			1	120	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	<u> </u>		52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	ta	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		27			

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ta

t_b

Reverse Recovery Fall Time

Reverse Recovery Rise Time

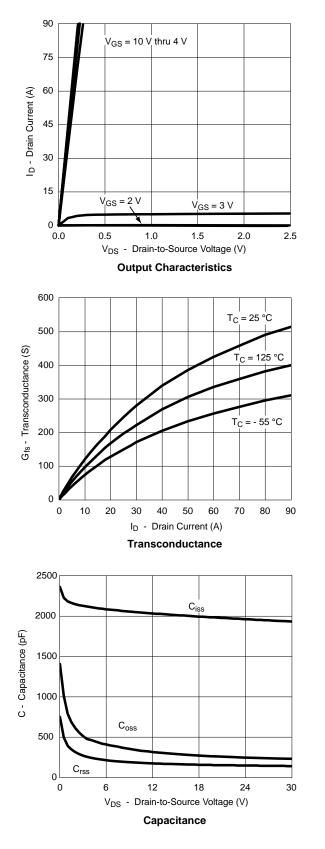
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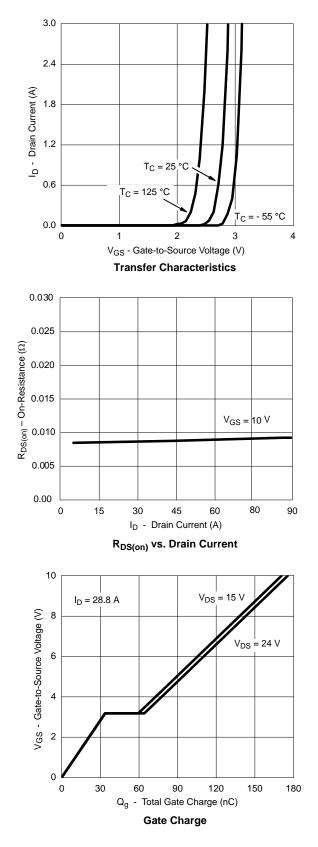
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25



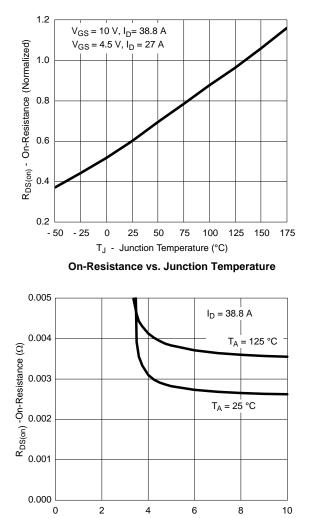
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



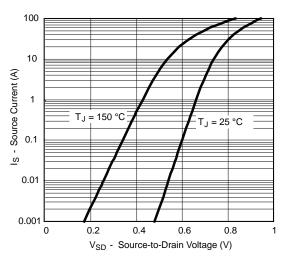




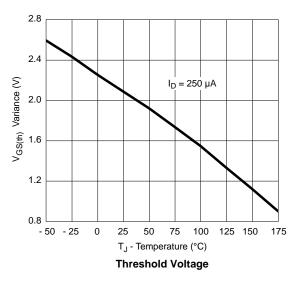
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

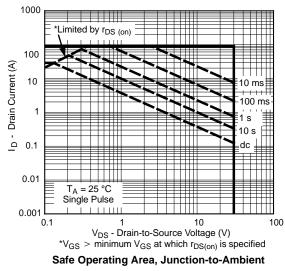


 V_{GS} - Gate-to-Source Voltage (V) R_{DS(on)} vs. V_{GS} vs. Temperature

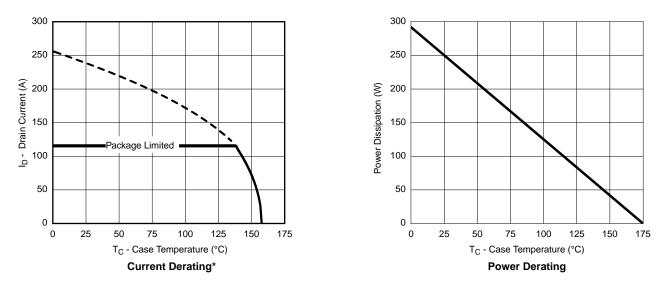


Forward Diode Voltage vs. Temperature



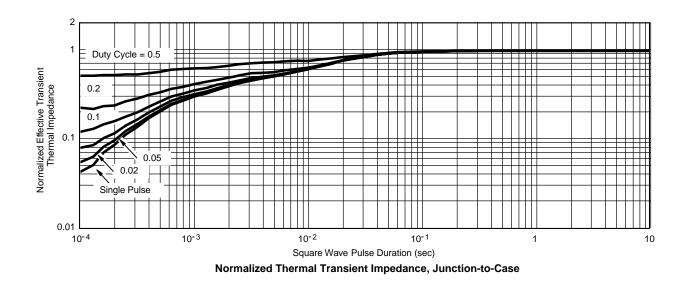






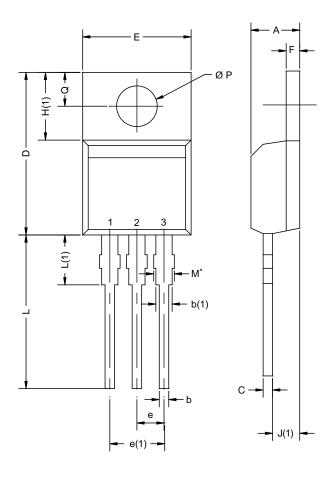
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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